

# **2025 IEEE 9th International Test Conference India (ITC India 2025)**

**Bangalore, India  
20-22 July 2025**



**IEEE Catalog Number: CFP25N34-POD  
ISBN: 979-8-3315-0130-3**

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IEEE Catalog Number:	CFP25N34-POD
ISBN (Print-On-Demand):	979-8-3315-0130-3
ISBN (Online):	979-8-3315-0129-7
ISSN:	2833-8383

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